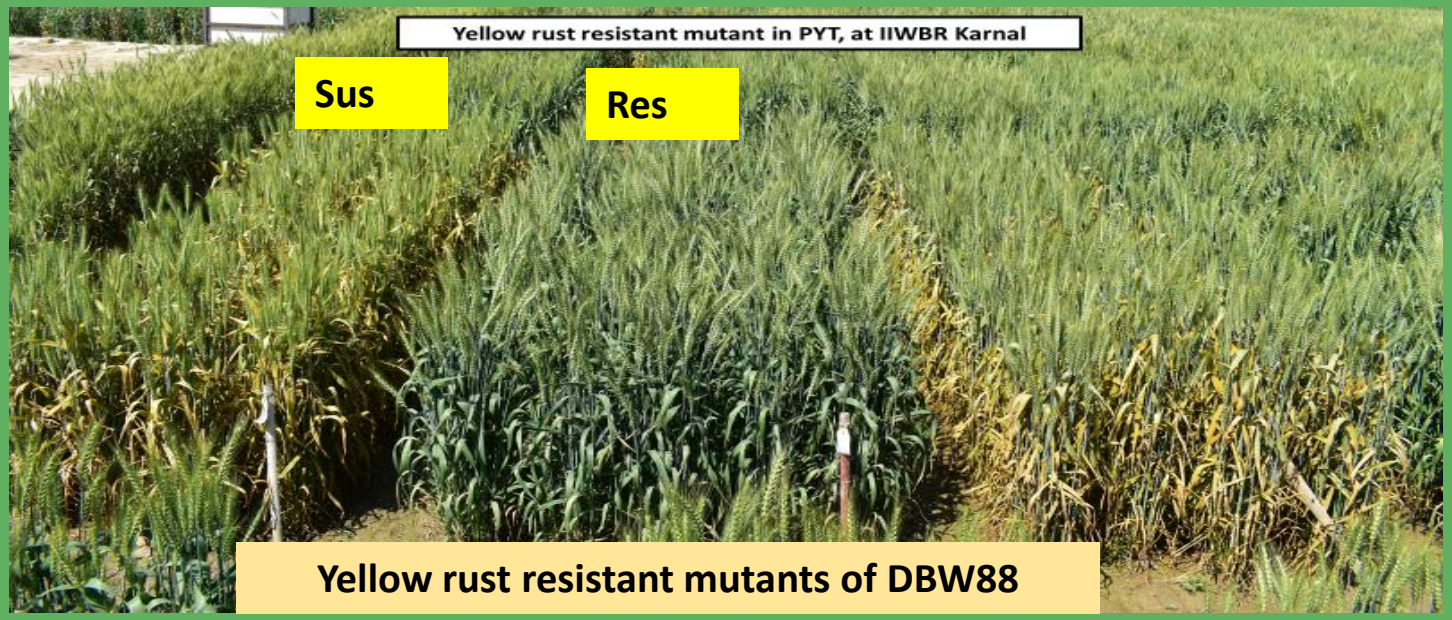
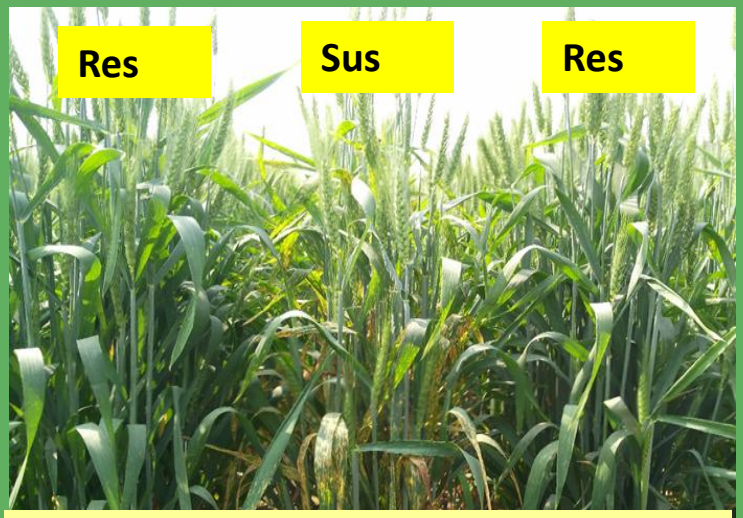
Development of Yellow Rust Resistant Mutant lines in Indian Wheat

(BARC- ICAR-IIWBR, Karnal collaboration)

In collaboration with ICAR-IIWBR, Karnal, using gamma ray induced mutagenesis, Yellow (Stripe) Rust resistant mutant lines have been developed in the background of recent elite wheat varieties (viz.DBW-88, HD-2967, WH1105). These mutant lines are now under evaluation for yield.

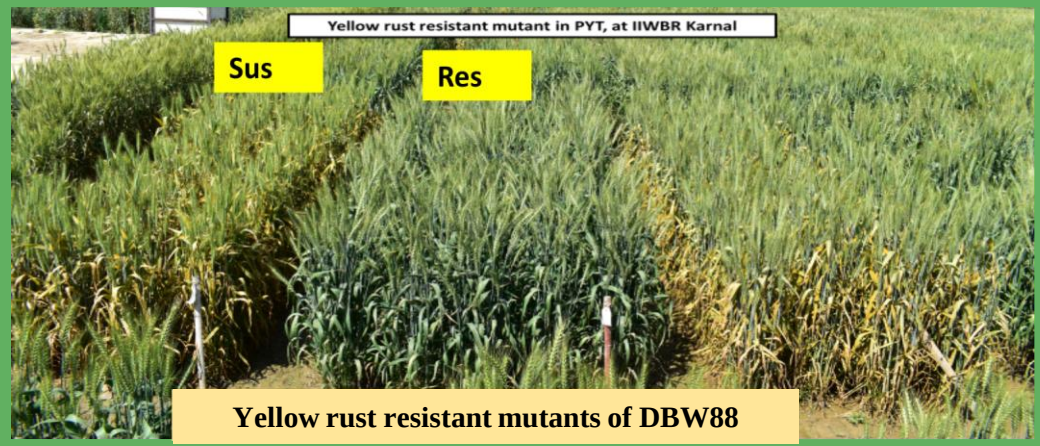


Yellow rust resistant mutants of DBW88



Yellow rust resistant mutants in HD2967

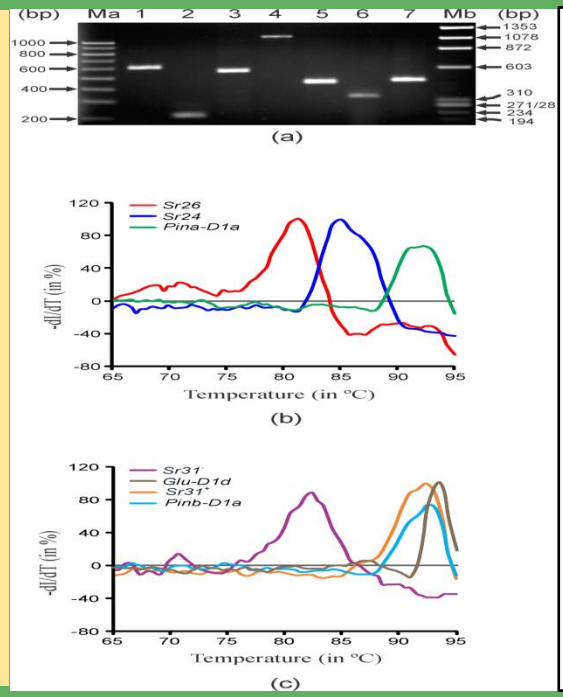
Yellow rust resistant mutants in WH1105

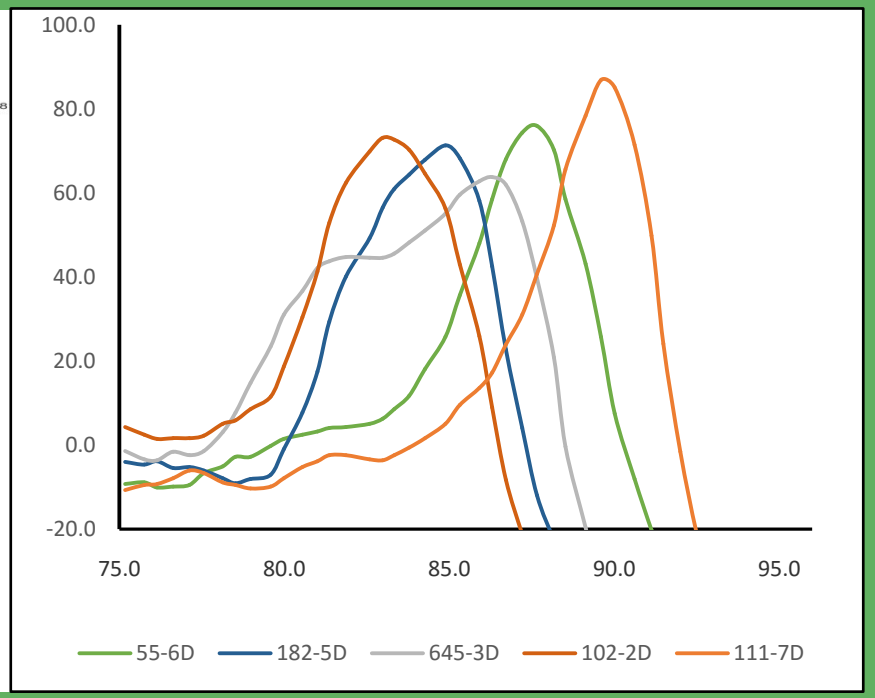


Yellow rust resistant mutants of DBW88

Gel -free screening of molecular markers in wheat
(NABTD-MBD collaboration)

- Use of SYBR Green Melt Curve Based Screening, gel free screening of molecular markers (SCAR &STMS) have been developed for wheat.





PLOS ONE

RESEARCH ARTICLE

GLADS: A gel-less approach for detection of STMS markers in wheat and rice

Gautam Vishwakarma[1,2☯], Ravi Prakash Sanyal[2,3☯], Ajay Saini[2,3], Parmeshwar Kumar Sahu[4], Ravi Raj Singh Patel[4], Deepak Sharma[4], Ratan Tiwari[5], Bikram Kishore Das[1,2*]

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RESEARCH ARTICLE

Validation and Marker-Assisted Selection of Stem Rust Resistance Gene *Sr2* in Indian Wheat Using Gel-Based and Gel-Free Methods

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Plant Breeding

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Rapid and convenient gel-free screening of SCAR markers in wheat using SYBR green-based melt-profiling

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